

Notice of References Cited	Application/Control No. 10/767,364	Applicant(s)/Patent Under Reexamination YEH ET AL.	
	Examiner Mei Q. Huang	Art Unit 1713	Page 1 of 1

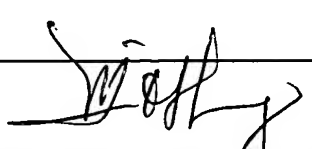
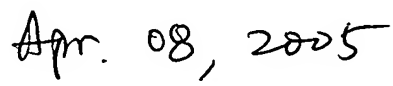
U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,309,707	10-2001	Mayer et al.	427/386
*	B	US-5,032,641	07-1991	Nanishi et al.	524/544
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP 06-345823	12-1994	Japan	Shunichi et al.	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	 

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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